PD-95760

International **tor** Rectifier

- Advanced Process Technology
- Surface Mount (IRF3315S)
- Low-profile through-hole (IRF3315L)
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

Description

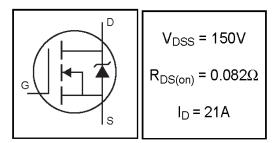
Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

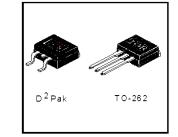
The D²Pak is a surface mount power package capable of accommodating die sizes up to HEX-4. It provides the highest power capability and the lowest possible on-resistance in any existing surface mount package. The D²Pak is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0W in a typical surface mount application.

The through-hole version (IRF3315L) is available for lowprofile applications.

IRF3315SPbF IRF3315LPbF

HEXFET[®] Power MOSFET





Absolute Maximum Ratings Parameter Units Max. I_D @ T_C = 25°C Continuous Drain Current, VGS @ 10VS 21 I_D @ T_C = 100°C Continuous Drain Current, VGS @ 10VS 15 А Pulsed Drain Current 00 84 I_{DM} $P_D @ T_A = 25^{\circ}C$ Power Dissipation 3.8 W $P_D @ T_C = 25^{\circ}C$ Power Dissipation 94 W Linear Derating Factor 0.63 WPC \bar{V}_{GS} Gate-to-Source Voltage ± 20 V Single Pulse Avalanche Energy 29 350 EAS mJ Avalanche Current® 12 А I_{AR} EAR Repetitive Avalanche Energy① 9.4 mJ dv/dt Peak Diode Recovery dv/dt 35 2.5 V/ns T_{.1} -55 to + 175 Operating Junction and Storage Temperature Range °C T_{STG} Soldering Temperature, for 10 seconds 300 (1.6mm from case)

Thermal Resistance

	Parameter	Тур.	Max.	Units
R _{0JC}	Junction-to-Case		1.6	00404
R _{OJA}	Junction-to-Ambient (PCB Mounted,steady-state)**		40	°CW

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Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	150			V	$V_{GS} = 0V, I_{D} = 250 \mu A$
$\Delta V_{(BR)DSS} / \Delta T_{\rm J}$	Breakdown Voltage Temp. Coefficient		0.187		V/°C	Reference to 25°C, I_D = 1mA ⁽⁵⁾
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.082	Ω	V _{GS} = 10V, I _D = 12A ④
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$
g fs	Forward Transconductance	17			S	$V_{DS} = 50V, I_{D} = 12A$
loss	Drain-to-Source Leakage Current			25	μA	V_{DS} = 150V, V_{GS} = 0V
				250		V_{DS} = 120V, V_{GS} = 0V, T_{J} = 125°C
1	Gate-to-Source Forward Leakage	——		100	nA	V _{GS} = 20V
IGSS	Gate-to-Source Reverse Leakage			-100		V _{GS} = -20V
Qg	Total Gate Charge			95		I _D = 12A
Q _{gs}	Gate-to-Source Charge			11	nC	V _{DS} = 120V
Qgd	Gate-to-Drain ("Miller") Charge			47		V _{GS} = 10V, See Fig. 6 and 13 @
t _{d(on)}	Turn-On Delay Time		9.6			V _{DD} = 75V
tr	RiseTime		32			I _D = 12A
t _{d(off)}	Turn-Off Delay Time		49		ns	$R_G = 5.1\Omega$
t _f	FallTime		38			R _D = 5.9Ω, See Fig. 10 ④⑤
L _S	Internal Source Inductance		7.5		nH	Between lead,
						and center of die contact
C _{iss}	Input Capacitance		1300			V _{GS} = 0V
C _{OSS}	Output Capacitance		300		pF	V _{DS} = 25V
Crss	Reverse Transfer Capacitance		160	——		f = 1.0MHz, See Fig. 5

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
k	Continuous Source Current			21		MOSFET symbol
	(Body Diode)		21	A	showing the	
I _{SM}	Pulsed Source Current			84		integral reverse 🏻 🖓 🛄
	(Body Diode) ①					p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_{J} = 25^{\circ}C, I_{S} = 43A, V_{GS} = 0V$ (4)
trr	Reverse Recovery Time	—	174	260	ns	T _J = 25°C, I _F = 43A
Q _{rr}	Reverse Recovery Charge		1.2	1.7	μC	di/dt = 100A/µs ⊕⑤
t _{on}	Forward Turn-On Time	Intrinsic tum-on time is negligible (turn-on is dominated by L_S+L_D)				

Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

④ Pulse width \leq 300µs; duty cycle \leq 2%.

- V_{DD} = 25V, starting T_J = 25°C, L = 4.9 mH $R_G = 25\Omega$, $I_{AS} = 12A$. (See Figure 12)
 - (5) Uses IRF3315 data and test conditions
- $\label{eq:ISD} \textcircled{3} \ \ \mathbb{I}_{\text{SD}} \leq 12 \text{A}, \ di/dt \leq 140 \text{A}/\mu \text{s}, \ \ V_{\text{DD}} \leq V_{(\text{BR})\text{DSS}},$ T_J≤175°C
- ** When mounted on 1" square PCB (FR-4 or G-10 Material).
 - For recommended footprint and soldering techniques refer to application note #AN-994.
 - 2

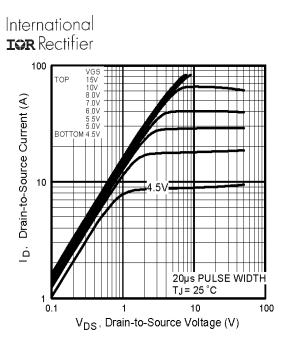


Fig 1. Typical Output Characteristics

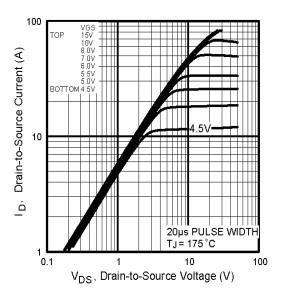


Fig 2. Typical Output Characteristics

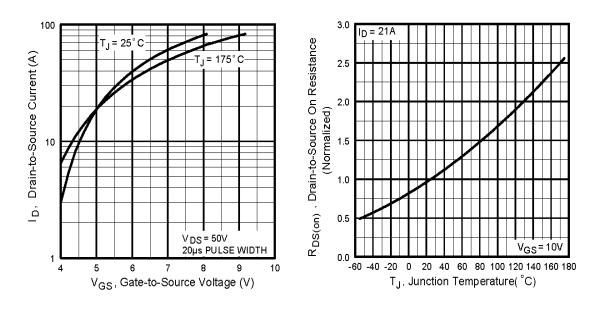
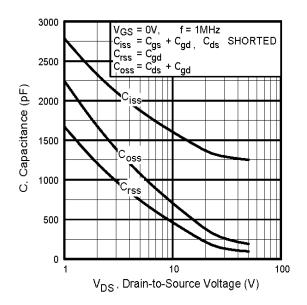
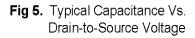


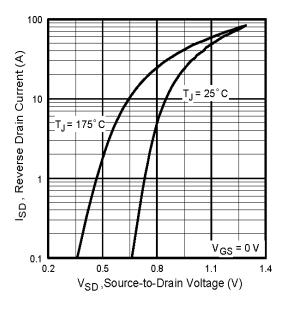
Fig 3. Typical Transfer Characteristics

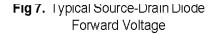
Fig 4. Normalized On-Resistance Vs. Temperature

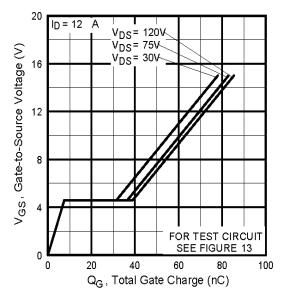
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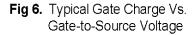












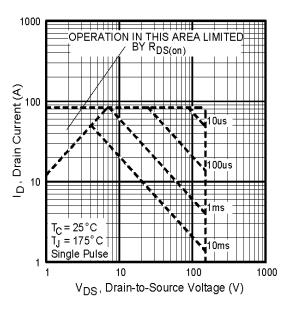


Fig 8. Maximum Safe Operating Area

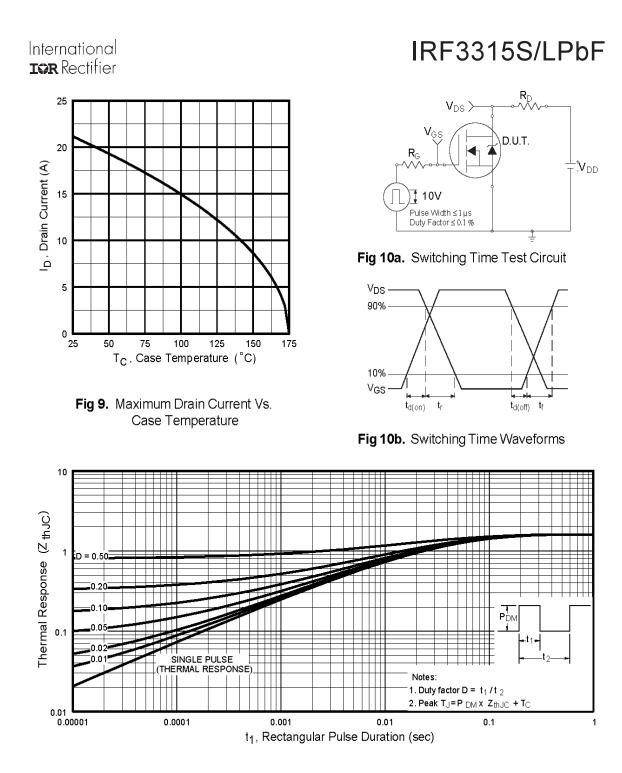


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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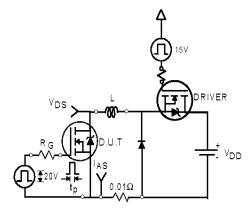


Fig 12a. Unclamped Inductive Test Circuit

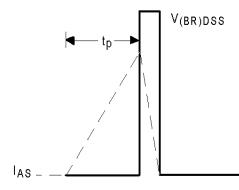


Fig 12b. Unclamped Inductive Waveforms

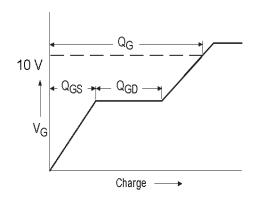


Fig 13a. Basic Gate Charge Waveform 6

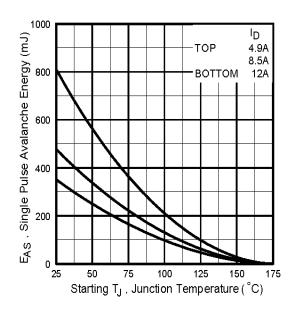


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

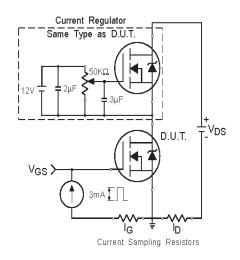
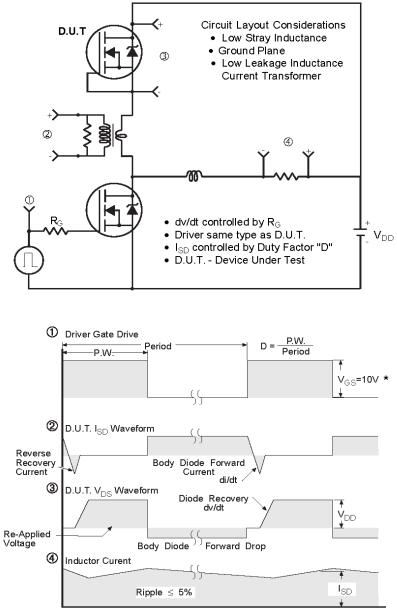


Fig 13b. Gate Charge Test Circuit

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IRF3315S/LPbF

Peak Diode Recovery dv/dt Test Circuit



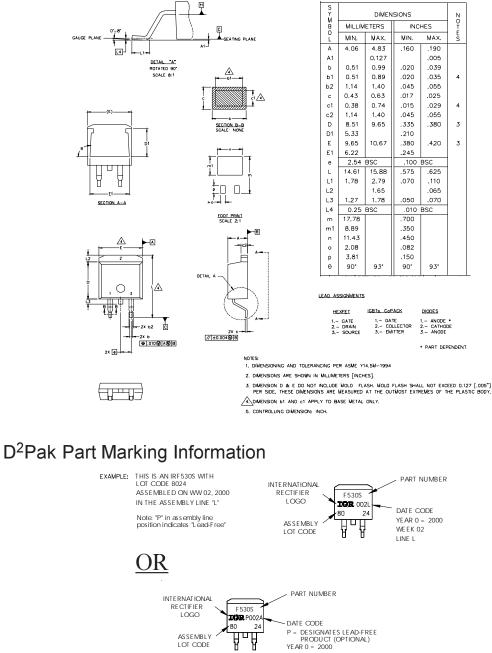
* $V_{\rm GS}$ = 5V for Logic Level Devices

Fig 14. For N-Channel HEXFETS

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D²Pak Package Outline

Dimensions are shown in millimeters (inches)



Å

WEEK 02

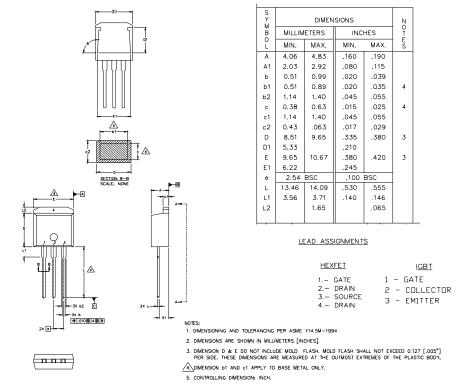
A = ASSEMBLY SITE CODE

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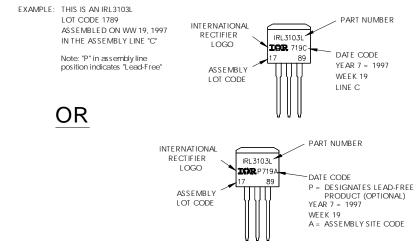
IRF3315S/LPbF

TO-262 Package Outline

Dimensions are shown in millimeters (inches)



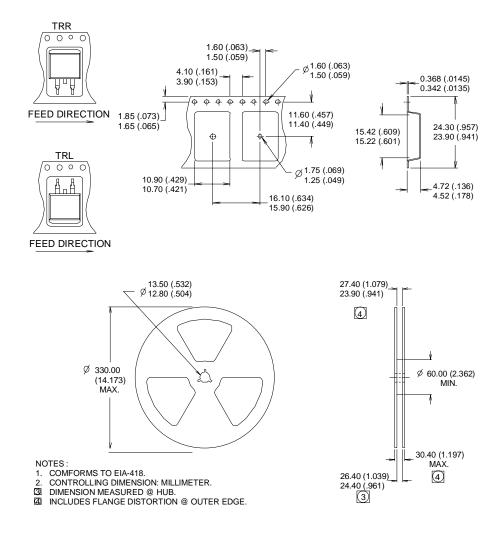
TO-262 Part Marking Information



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D²Pak Tape & Reel Information

Dimensions are shown in millimeters (inches)



Data and specifications subject to change without notice.

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